Supporting Information

In Situ Studies of the Cathodic Stability of Single-Crystalline IrO₂(110) Ultrathin Films Supported on RuO₂(110)/Ru(0001) in an Acidic Environment

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Figure S2: Ball and stick model of the $IrO_2(110)$ surface. The grey and red spheres represent the iridium and oxygen atoms, respectively. The coordinate system gives the relevant crystallographic directions.

Figure S2 shows the rutile $IrO_2(110)$ surface with the relevant crystallographic directions given in the coordinate system. The *h* and *l* directions in reciprocal space correspond to the crystallographic [110] and [110] directions, respectively. For this reason, *h*- and *l*-scans allow to derive the lattice parameters and domain sizes in each direction from the peak positions and FWHM values, respectively, and to monitor possible alterations of them upon cathodic polarization. The *k* direction in reciprocal space corresponds to the crystallographic [001] direction. However, in the present study *k*-scans were not conducted.



Figure S3: Current-potential diagram of the $IrO_2(110)$ -RuO₂(110)/Ru(0001) model electrode within the in situ experiments.



Figure S4: Schematic representation of the four-layer model employed for the simulation of the XRR data of the $IrO_2(110)$ -RuO₂(110)/Ru(0001) model electrode (modified and reprinted with permission from Weber et al.¹ Copyright 2019 American Chemical Society).

at open-circuit potential (OCP) and -0.14 V vs. SHE. The X-ray beam with an energy of 21.5 keV (λ = 57.67 pm) was modelled with a Gaussian shape, the beam with was set 200 µm. The values highlighted in orange or blue either hit the default limit or were kept constant, respectively. *d* denotes the thickness of a specific layer, σ the roughness, and *dens* the density in formula units (FU) per cubic angstrom. The intensity of the incident beam and the background intensity are denoted as I_0 and I_{bkg} , respectively. The quality of a fit is given as FOM log (FOM = Figure Of Merit).

	ОСР	-0.14 V
rooflike IrO ₂ (110)		
<i>d</i> / Å	24.6	23.9
σ / Å	8.9	9.0
dens / FU·Å ⁻³	0.0182	0.0129
flat IrO ₂ (110)		
<i>d</i> / Å	48.3	50.6
σ / Å	13.3	17.3
dens / FU·Å ⁻³	0.0312	0.0312
RuO ₂ (110)		
<i>d</i> / Å	19.9	19.9
σ / Å	7.4	6.9
dens / FU·Å ⁻³	0.0311	0.0319
RuO ₂ interlayer		
<i>d</i> / Å	2.5	2.5
σ / Å	2.0	2.0
<i>dens /</i> FU·Å ⁻³	0.0344	0.0331
Ru(0001) substrate		
σ / Å	54.7	56.7
inst.set		
Io	6.15.106	6.92.106
Ibkg	1.66	1.59
FOM log	3.05.10-2	$2.35 \cdot 10^{-2}$

For the fitting of the XRR data the software package GenX^2 (v. 2.4.10) was utilized. A fourlayer model (cf. **Figure S4**) similar to that of a previous contribution¹ was employed. Two of the layers were introduced as IrO_2 layers, the other two as RuO_2 layers. The substrate was set to metallic Ru while H₂O was employed as ambient medium. After editing the instrument parameters (wavelength, beam width/shape) and applying the fit model each imported data set was fitted manually until a rough visual agreement of the experimental data and the fit was achieved. After that the automated fitting function of GenX^2 was started and run for at least 1,000 generations. This procedure of manual and automated fitting was repeated until the experimental and fitted XRR curves were in sufficient agreement and reasonable parameters for the fit model were obtained.



Figure S5: Experimental ("expt.") electron density profiles (solid lines) as obtained from the XRR fits at OCP and -0.14 V. For comparison, the bulk electron densities of Ru, RuO₂, and IrO₂ are shown (dashed line). *z* denotes the distance from the Ru(0001) substrate surface.

Figure S5 shows the experimental electron density profiles as derived from the fits of the XRR data at OCP (blue solid line) and -0.14 V (red solid line). For comparison, the bulk electron densities of Ru, RuO₂, and IrO₂ (black dashed line) are given. The profiles illustrate the layered structure of the model electrode. The apparently large discrepancy between the expected bulk and fitted densities for RuO2 and IrO2 in **Figure S5** is partly due to the way the plot is generated from the fitted densities, thicknesses and roughness for each slab in the model.

Table S2: Fitting parameters (CasaXPS, v. 2.3.18) of the XPS data (Ir 4f and O 1s) of the $IrO_2(110)$ -RuO₂(110)/Ru(0001) model electrode before and after the in situ experiments. The functions for the Line Shapes are adapted from literature^{3,4} and the obtained binding energies can be compared with literature^{3,5,6}.

freshly prepared					
component	BE / eV	FWHM	Line Shape		
Ir 4f					
Ir ^{IV} 4f _{7/2}	61.7	1.4	LF(0.3, 1.2, 55, 200)		
$Ir^{IV} 4f_{5/2}$	64.7	1.4	LF(0.3, 1.2, 55, 200)		
$Ir^{IV} 5p_{1/2}$	64.7	4.5	GL(30)		
		O 1s			
O ^{II–}	530.0	1.3	LF(0.37, 1.2, 25, 110)		
after in situ experiments					
after in situ	experimen	ts			
component	experimen BE / eV	ts FWHM	Line Shape		
after in situ component	experimen BE / eV	ts FWHM Ir 4f	Line Shape		
after in situ component Ir ^{IV} 4f _{7/2}	BE / eV	ts FWHM Ir 4f 1.3	Line Shape		
after in situcomponentIr ^{IV} 4f _{7/2} Ir ^{IV} 4f _{5/2}	experimen BE / eV 61.7 64.7	ts FWHM Ir 4f 1.3 1.4	Line Shape LF(0.3, 1.2, 55, 200) LF(0.3, 1.2, 55, 200)		
after in situcomponentIr ^{IV} 4f _{7/2} Ir ^{IV} 4f _{5/2} Ir ^{IV} 5p _{1/2}	experimen BE / eV 61.7 64.7 64.7	ts FWHM Ir 4f 1.3 1.4 4.5	Line Shape LF(0.3, 1.2, 55, 200) LF(0.3, 1.2, 55, 200) GL(30)		
after in situ component Ir ^{IV} 4f _{7/2} Ir ^{IV} 4f _{5/2} Ir ^{IV} 5p _{1/2}	experimen BE / eV 61.7 64.7 64.7	ts FWHM Ir 4f 1.3 1.4 4.5 O 1s	Line Shape LF(0.3, 1.2, 55, 200) LF(0.3, 1.2, 55, 200) GL(30)		
after in situ component Ir ^{IV} 4f _{7/2} Ir ^{IV} 4f _{5/2} Ir ^{IV} 5p _{1/2} O ^{II–}	experimen BE / eV 61.7 64.7 64.7 530.0	ts FWHM Ir 4f 1.3 1.4 4.5 O 1s 1.4	Line Shape LF(0.3, 1.2, 55, 200) LF(0.3, 1.2, 55, 200) GL(30) LF(0.37, 1.2, 25, 110)		



Figure S6: XP spectra in the binding energy region of Ir 4d, Ru 3d, and C 1s of the $IrO_2(110)$ -RuO₂(110)/Ru(0001) model electrode before (top) and after (bottom) the in situ experiments. The positions of the Ru 3d signals of Ru(0001) and RuO₂(110) are indicated by dashed blue and red lines, respectively.

The XP spectrum of the freshly prepared model electrode (cf. top of **Figure S6**) reveals two peaks at binding energies of 298.1 eV and 314.0 eV, corresponding to the Ir $4d_{5/2}$ and Ir $4d_{3/2}$ signal, respectively.³ The dashed blue and red lines indicate the positions of the Ru 3d signals corresponding to Ru(0001) and RuO₂(110), respectively.^{4,7} Since the C 1s signal is overlapping with the Ru $3d_{3/2}$ peak, the intensity ratio due to spin orbit splitting of the Ru 3d signal is not preserved.

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